

**Search Notes**

Application/Control No.

10/812,185

Examiner

John D. Lee

Applicant(s)/Patent under  
Reexamination

FUJIOKA ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
359	326,332	12/13/2005	JDL
372	3,6,7	12/13/2005	JDL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched; search strategy on separate sheet.	12/13/2005	JDL